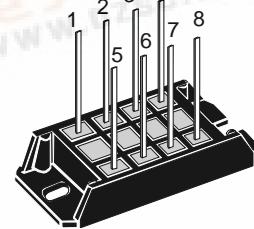
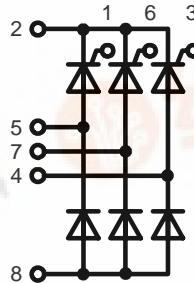


Three Phase Half Controlled Rectifier Bridge

I_{dAVM} = 27 A
V_{RRM} = 1200-1600 V

V _{RSM} V _{DSM}	V _{RRM} V _{DRM}	Type
V	V	
1300	1200	VVZ 24-12io1
1500	1400	VVZ 24-14io1
1700	1600	VVZ 24-16io1



Symbol	Test Conditions	Maximum Ratings		
I _{dAV}	T _K = 100°C; module	21	A	
I _{dAVM}	module	27	A	
I _{FRMS} , I _{TRMS}	per leg	16	A	
I _{FSM} , I _{TSM}	T _{VJ} = 45°C; V _R = 0	t = 10 ms (50 Hz), sine t = 8.3 ms (60 Hz), sine	300 320	A A
	T _{VJ} = T _{VJM} V _R = 0	t = 10 ms (50 Hz), sine t = 8.3 ms (60 Hz), sine	270 290	A A
I ² t	T _{VJ} = 45°C V _R = 0	t = 10 ms (50 Hz), sine t = 8.3 ms (60 Hz), sine	450 430	A ² s A ² s
	T _{VJ} = T _{VJM} V _R = 0	t = 10 ms (50 Hz), sine t = 8.3 ms (60 Hz), sine	365 350	A ² s A ² s
(di/dt) _{cr}	T _{VJ} = T _{VJM} f = 400 Hz, t _p = 200 μs V _D = 2/3 V _{DRM} I _G = 0.3 A, di _G /dt = 0.3 A/μs	repetitive, I _T = 50 A non repetitive, I _T = 1/3 • I _{dAV}	150 500	A/μs A/μs
(dv/dt) _{cr}	T _{VJ} = T _{VJM} ; V _{DR} = 2/3 V _{DRM} R _{GK} = ∞; method 1 (linear voltage rise)		1000	V/μs
V _{RGM}			10	V
P _{GM}	T _{VJ} = T _{VJM} I _T = I _{TAVM}	t _p = 30 μs t _p = 500 μs t _p = 10 ms	≤ 10 ≤ 5 ≤ 1	W W W
P _{GAVM}			0.5	W
T _{VJ}			-40...+125	°C
T _{VJM}			125	°C
T _{stg}			-40...+125	°C
V _{ISOL}	50/60 Hz, RMS I _{ISOL} ≤ 1 mA	t = 1 min t = 1 s	3000 3600	V~ V~
M _d	Mounting torque (M5) (10-32 UNF)		2-2.5 18-22	Nm lb.in.
Weight	typ.		28	g

Data according to IEC 60747 and refer to a single thyristor/diode unless otherwise stated.
IXYS reserves the right to change limits, test conditions and dimensions.

Features

- Package with DCB ceramic base plate
- Isolation voltage 3600 V~
- Planar passivated chips
- Soldering terminals
- UL registered E 72873

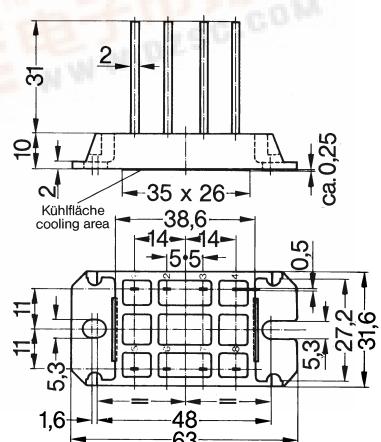
Applications

- Input rectifier for switch mode power supplies (SMPS)
- Softstart capacitor charging
- Electric drives and auxiliaries

Advantages

- Easy to mount with two screws
- Space and weight savings
- Improved temperature and power cycling

Dimensions in mm (1 mm = 0.0394")



Symbol	Test Conditions	Characteristic Values		
I_R, I_D	$V_R = V_{RRM}; V_D = V_{DRM}$ $T_{VJ} = T_{VJM}$ $T_{VJ} = 25^\circ C$	\leq	5	mA
		\leq	0.3	mA
V_F, V_T	$I_F, I_T = 30 A, T_{VJ} = 25^\circ C$	\leq	1.45	V
V_{TO}	For power-loss calculations only		1	V
r_T	$(T_{VJ} = 125^\circ C)$		16	$m\Omega$
V_{GT}	$V_D = 6 V;$ $T_{VJ} = 25^\circ C$ $T_{VJ} = -40^\circ C$	\leq	1.0	V
I_{GT}	$V_D = 6 V;$ $T_{VJ} = 25^\circ C$ $T_{VJ} = -40^\circ C$ $T_{VJ} = 125^\circ C$	\leq	65	mA
		\leq	80	mA
		\leq	50	mA
V_{GD}	$T_{VJ} = T_{VJM};$ $T_{VJ} = T_{VJM};$	\leq	0.2	V
I_{GD}	$V_D = 2/3 V_{DRM}$ $V_D = 2/3 V_{DRM}$	\leq	5	mA
I_L	$I_G = 0.3 A; t_G = 30 \mu s$ $di_G/dt = 0.3 A/\mu s$	$T_{VJ} = 25^\circ C$ $T_{VJ} = -40^\circ C$ $T_{VJ} = 125^\circ C$	\leq	150 mA 200 mA 100 mA
I_H	$T_{VJ} = 25^\circ C; V_D = 6 V; R_{GK} = \infty$		\leq	100 mA
t_{gd}	$T_{VJ} = 25^\circ C; V_D = 1/2 V_{DRM}$ $I_G = 0.3 A; di_G/dt = 0.3 A/\mu s$		\leq	2 μs
t_q	$T_{VJ} = 125^\circ C; I_T = 15 A, t_p = 300 \mu s, -di/dt = 10 A/\mu s$		typ.	150 μs
Q_r	$V_R = 100 V, dv/dt = 20 V/\mu s, V_D = 2/3 V_{DRM}$			75 μC
R_{thJC}	per thyristor (diode); DC current			2.1 K/W
	per module			0.35 K/W
R_{thJH}	per thyristor (diode); DC current			2.7 K/W
	per module			0.45 K/W
d_s	Creeping distance on surface			7 mm
d_A	Creepage distance in air			7 mm
a	Max. allowable acceleration			50 m/s ²

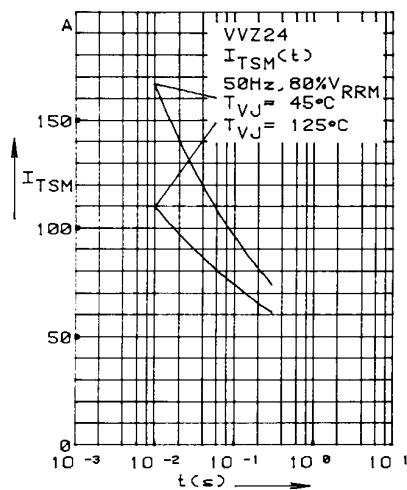


Fig. 1 Surge overload current per chip
 I_{TSM} : Crest value, t : duration

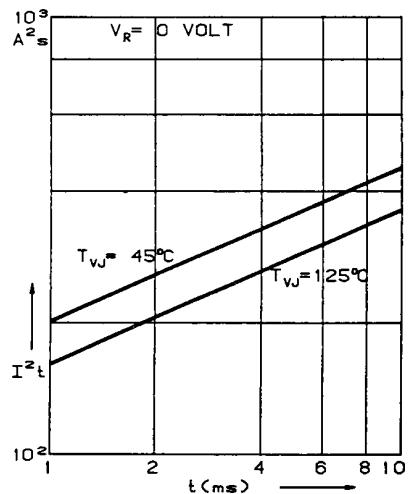


Fig. 2 I^2t versus time (1-10 ms)
per chip

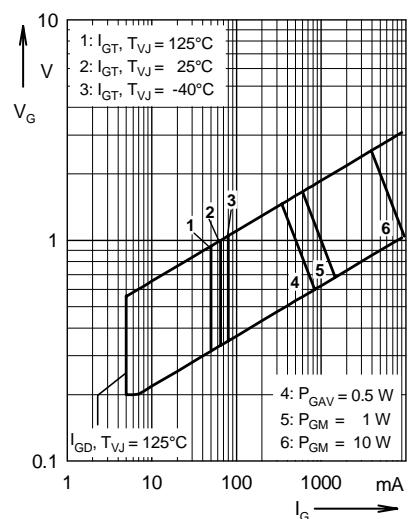


Fig. 3 Gate trigger characteristics
Triggering:

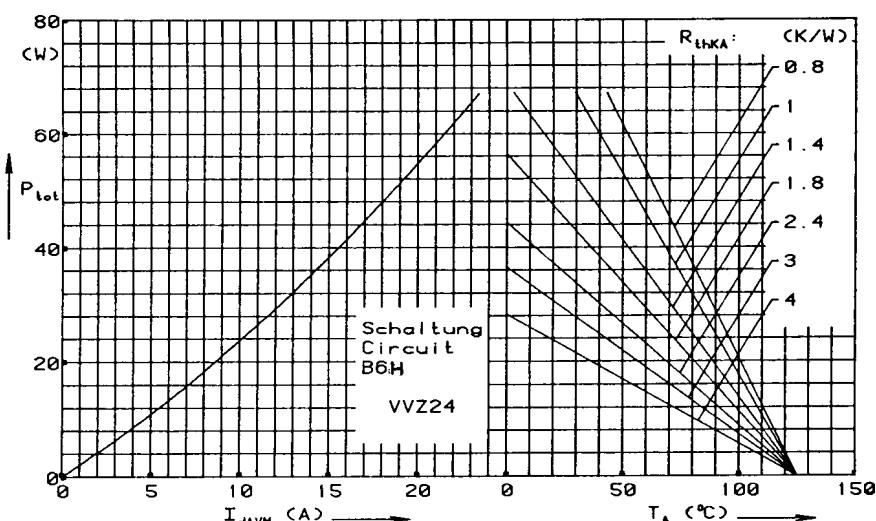


Fig. 4 Power dissipation versus direct output current and ambient temperature

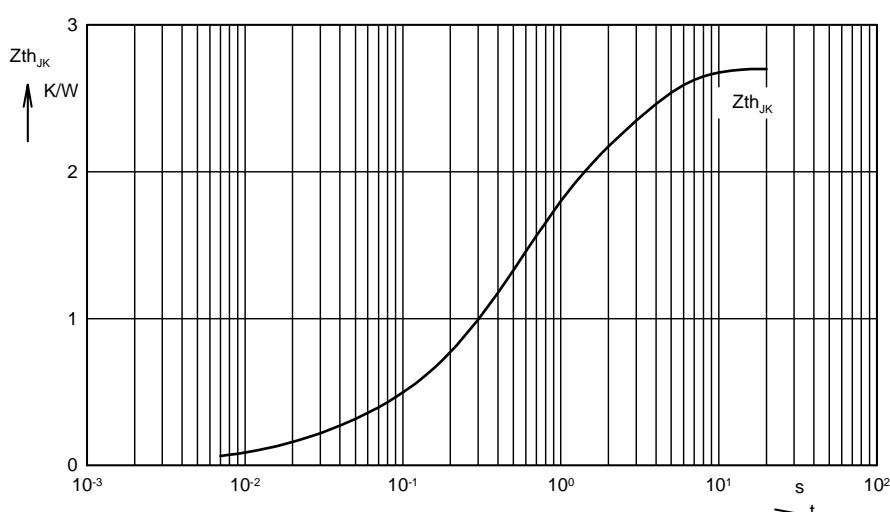


Fig. 5 Transient thermal impedance junction to heatsink

Constants for Z_{thJK} calculation

i	R_{thi} (K/W)	t_i (s)
1	0.17	0.028
2	1.4	0.44
3	1.1	2.6